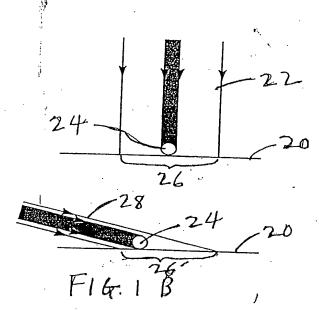
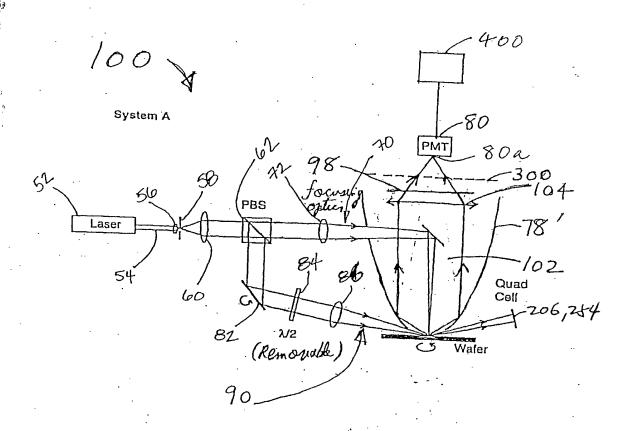
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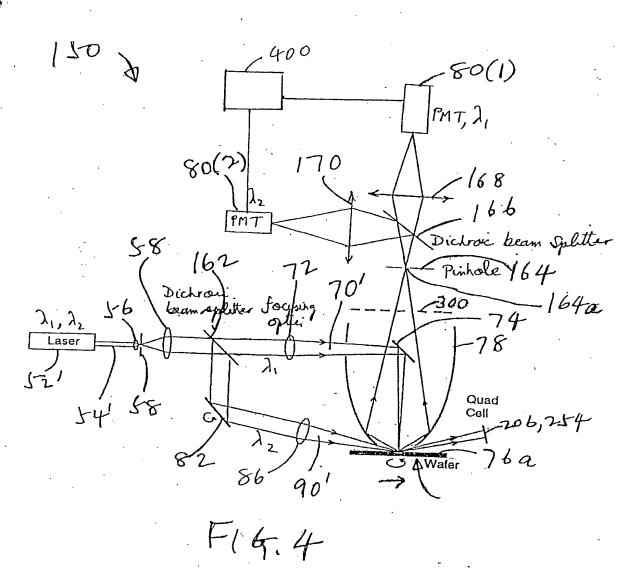
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24'
30

F19.21



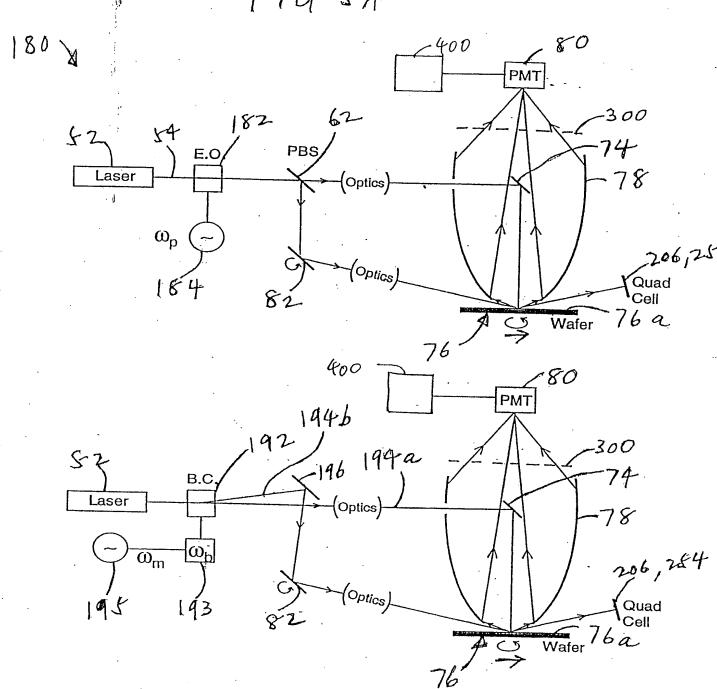
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90a 70a 76a 90 F164. 3

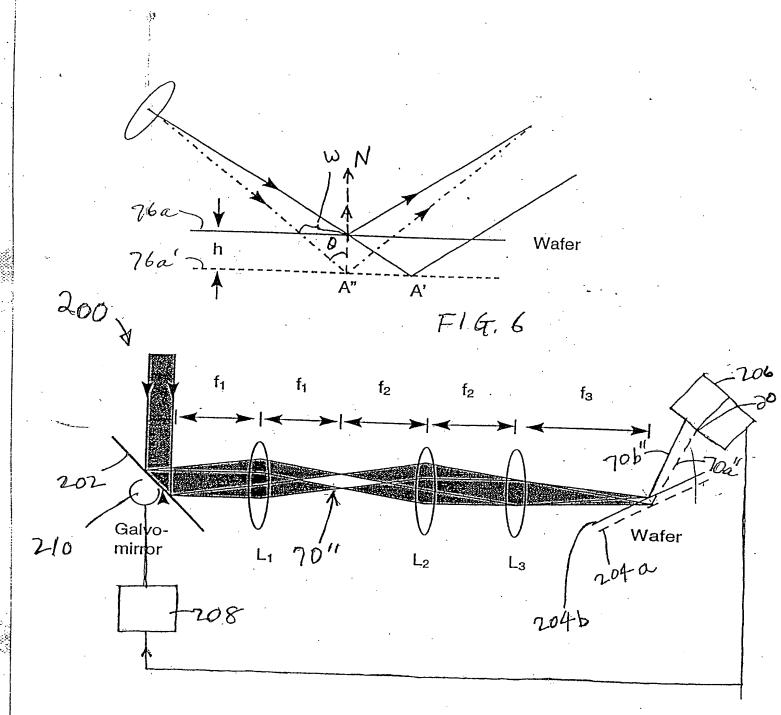


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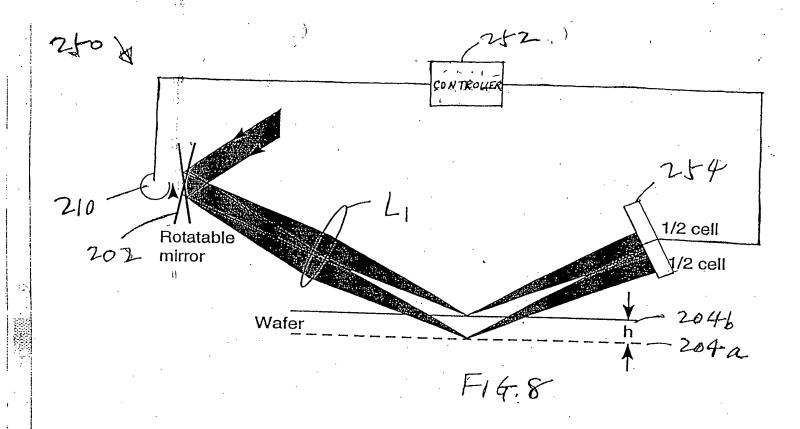
F16 5A



F14.5B



F14.7



F14. 9B

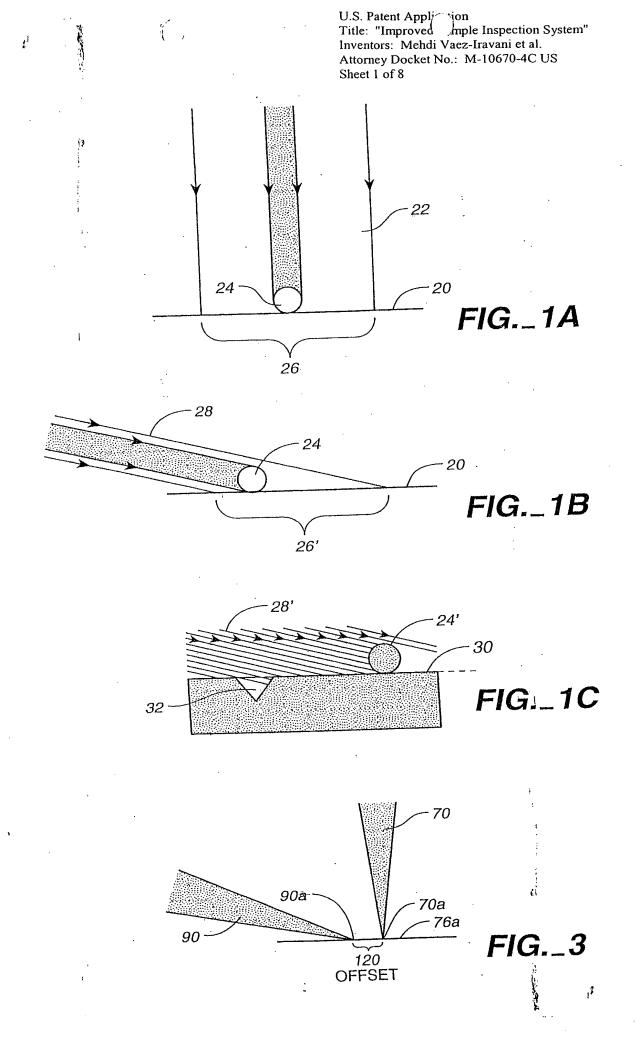
350 354 352 F16. 10A

350 354(i+i)
354(i+i)
354(i+i)
354(i+i)
360

Flat OB grammable fetter
Signarted programmable fetter

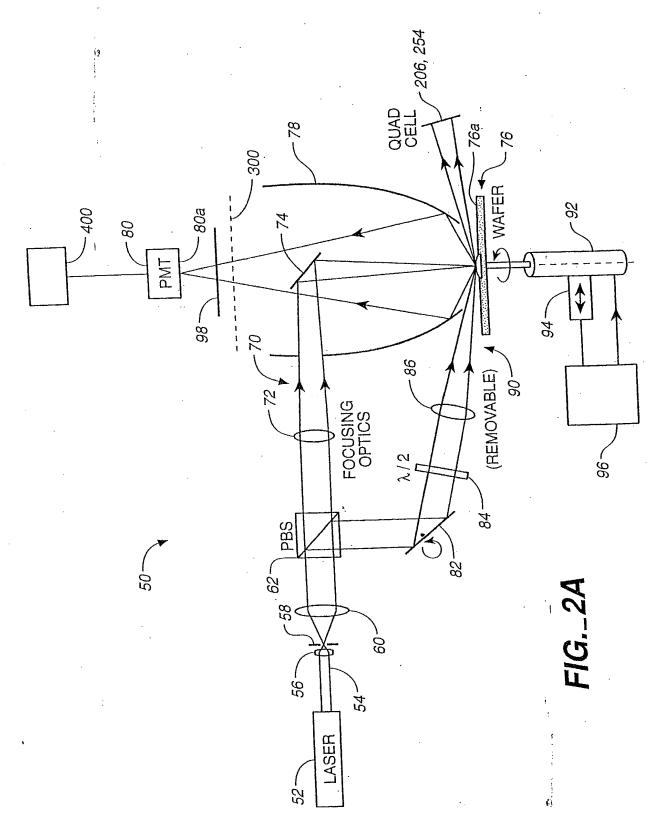
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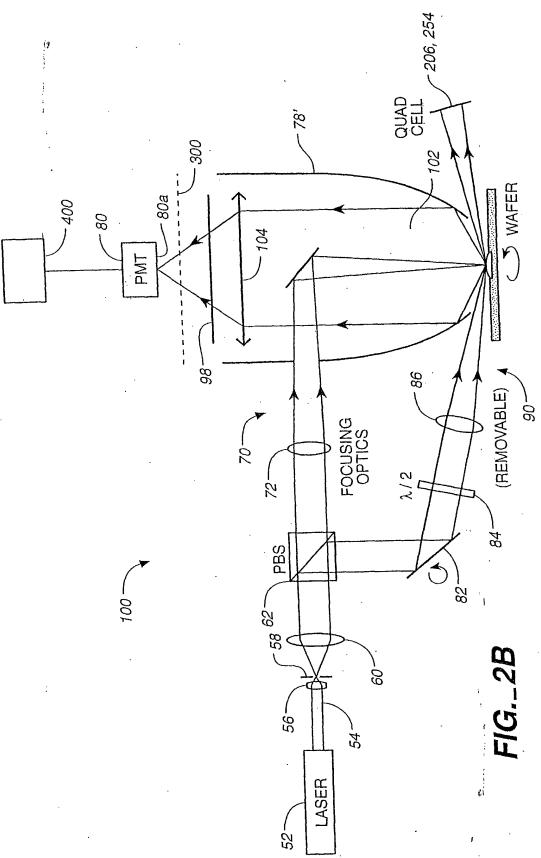


U.S. Patent Applicion
Title: "Improved apple Inspection System"
Inventors: Mehdi Vaez-Iravani et al.
Attorney Docket No.: M-10670-4C US
Sheet 2 of 8

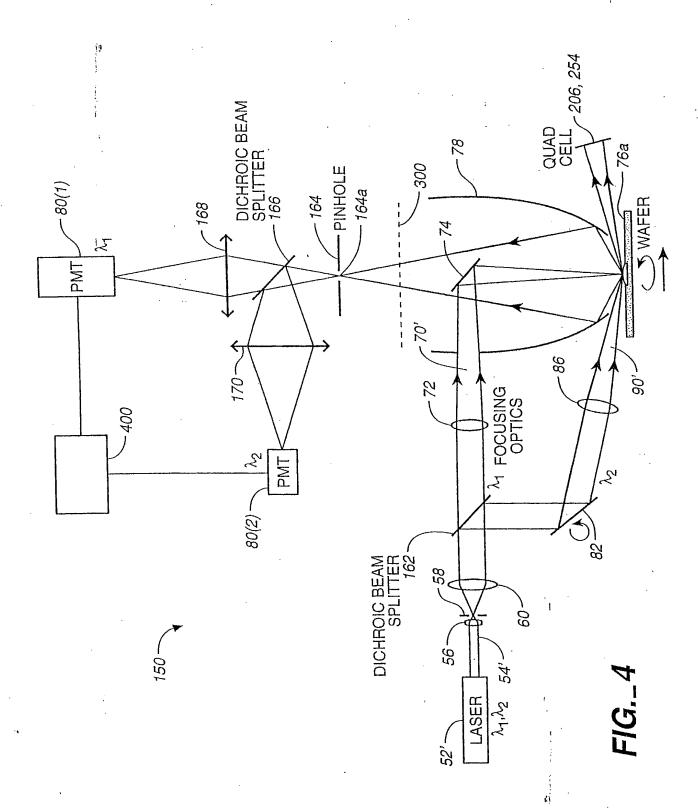
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Title: "Improved Sample Inspection System"
Inventors: Mehdi Vaez-Iravani et al.
Attorney Docket No.: M-10670-4C US
Sheet 3 of 8

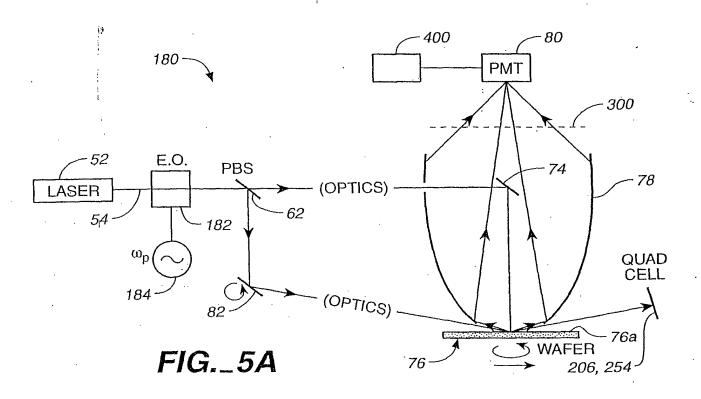


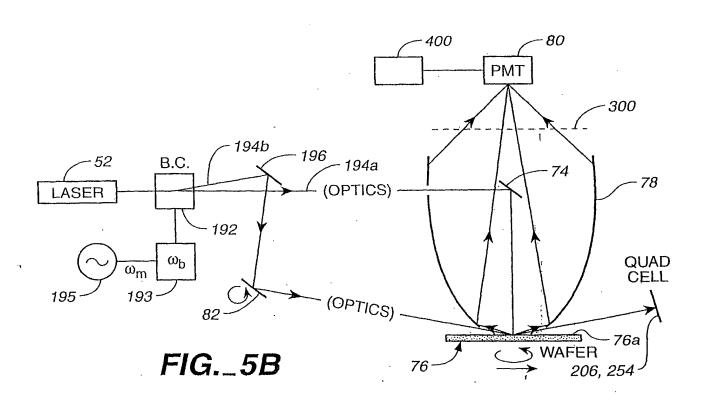
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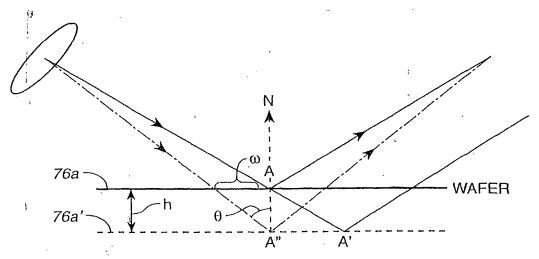


FIG._6

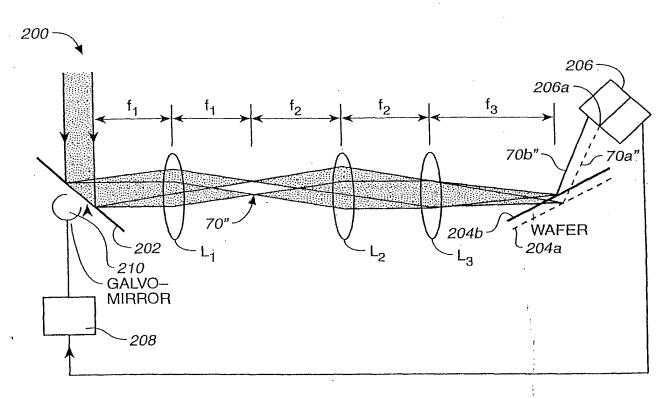
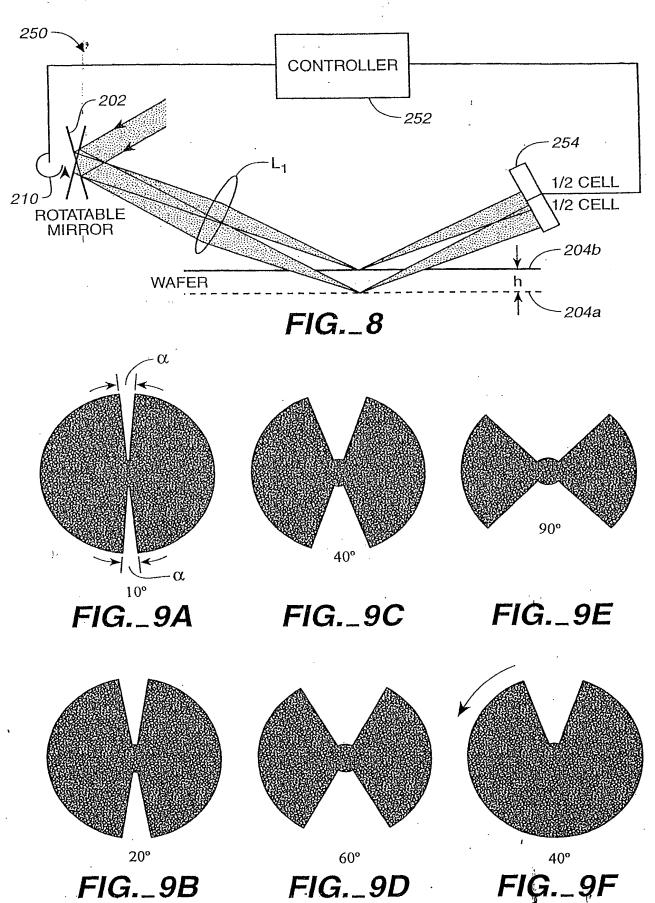


FIG._7

;7

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U.S. Patent Appli pn
Title: "Improved apple Inspection System"
Inventors: Mehdi Vaez-Iravani et al.

Attorney Docket No.: M-10670-4C US

Sheet 8 of 8

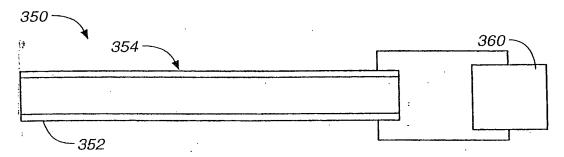
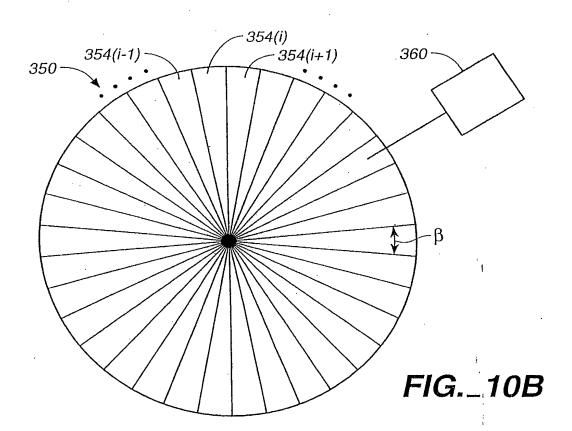


FIG._10A



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